

<b>Notice of References Cited</b>	Application/Control No. 09/204,364	Applicant(s)/Patent Under Reexamination HUR, YONG-WOO	
	Examiner Jeffrey R. Snay	Art Unit 1743	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0000458	01-2003	Marumo et al.	117/200
	B	US-3,520,656	07-1970	YATES PAUL C; et. al.	423/345
	C	US-5,686,314	11-1997	Miyazaki, Kunihiro	436/177
	D	US-6,290,777	09-2001	Imaoka et al.	134/1
	E	US-6,896,744	05-2005	Morinaga et al.	134/28
	F	US-5,560,857	10-1996	Sakon et al.	510/175
	G	US-5,294,763	03-1994	Chamberlain et al.	219/729
	H	US-5,026,135	06-1991	Booth, Bruce L.	385/130
	I	US-5,877,027	03-1999	Kemmochi et al.	436/175
	J	US-2002/0101576	08-2002	Shabani et al.	356/36
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Maxfield, B.W. et al "Superconducting Penetration Depth of Niobium" Physical Review, Vol. 139 (1965) pp. A 1515-A 1522.
	V	Kunze, J. et al. "Determination of titanium and zirconium wear debris in blood serum by means of HNO <sub>3</sub> /HF pressurized digestion using ICP - optical emission spectroscopy" Fresenius' Journal of Analytical Chemistry, Vol. 361 (July 1988) abstract only.
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.